



Revision Change Notice #1609272

Register today to create your account on Silabs.com. Your personalized profile allows you to receive technical document updates, new product announcements, "how-to" and design documents, product change notices (PCN) and other valuable content available only to registered users.

<http://www.silabs.com/profile>

PCN Date: 9/27/2016		Effective Date: 1/2/2017	
Title: CPT007B Revision A02			
PCN Type:			
<input checked="" type="checkbox"/> Datasheet			
<input checked="" type="checkbox"/> Product Revision			
PCN Details			
Description of Change:			
Silicon Labs is pleased to announce revision A02 of CPT007B devices and revision 1.2 of the corresponding datasheet for these products.			
The CPT007B A01 devices spend more time than intended in active and optimized active modes when performing sleep mode scans. This causes the overall current consumption of the A01 devices to increase. Revision A02 resolves the current consumption issue in Revision A01.			
After the effective date of this PCN, Silicon Labs reserves the right to deliver CPT007B-A02-GM for customers ordering CPT007B-A01-GM.			
Reason for Change:			
CPT007B Rev A02 release CPT007B Datasheet 1.2 release			
Impact on Form, Fit, Function, Quality, Reliability:			
There is no impact to form, fit, quality and reliability			
Product Identification:			
Existing Part Number		Replacement Part Number	Drop in Compatible Indicator
CPT007B-A01-GM		CPT007B-A02-GM	Yes
CPT007B-A01-GMR		CPT007B-A02-GMR	Yes
Note: The part numbers above include tape and reel variants which are denoted with an "R" at the end of the orderable part number.			
Last Date of Unchanged Product: 1/2/2017			
Qualification Samples:			
Samples are available now. Please contact your Silicon Labs sales representative to order samples. A list of Silicon Labs sales representatives is available at www.silabs.com .			

Appendix

CPTxxx Qualification Report



W7101F1 - Product Qualification Report Record Rev. H

The information contained in this document is PROPRIETARY to Silicon Laboratories, Inc. and shall not be reproduced or used in part or whole without Silicon Laboratories' written consent. The document is uncontrolled if printed or electronically saved.

CPTxxx, TSMC 0.18um Fabrication							
Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status
Test Group A – Accelerated Environment Stress Tests- ASECL - QFN- CuPd Wire							
HAST	JA110 100°C, 85%RH Vcc=3.6V, 264 hours	3 lots, N=>25	Q33300	0/40	1		
			Q33303	0/40	1		
			Q33411	0/40	1		
			Q33408	0/40	1	5 lots	Pass
			Q33138	0/40	1	0/200	
Temp Cycle	JA104 Cond C: -65°C to 150°C 500 cycles	3 lots, N=>25	Q33302	0/40	1		
			Q33413	0/40	1		
			Q33410	0/40	1	4 lots	Pass
			Q33337	0/29	1	0/149	
HTSL	JA103 150°C, 1000hr	3 lots, N=>25	Q33412	0/40			
			Q33409	0/40		3 lots	Pass
			Q33336	0/28		0/108	
Test Group B – Accelerated Lifetime Simulation Tests							
HTOL	JA108 T _J ≥ 125°C, Dynamic Vcc=3.6V, 1000 hours	3 lots, N=>77	Q27065	0/88			
			Q28301	0/80		3 lots	Pass
			Q28955	0/80		0/248	
LTOL	JA108 T _A = -10°C, Dynamic Vcc=3.6V, 1000 hours	1 lot, N=>32	Q25548	0/39		1 lots 0/39	Pass
ELFR	JA108 T _J ≥ 125°C, Dynamic Vcc=3.6V, 48 hours	3 lots, N=>500	Q27592	0/520			
			Q28218	0/514			
			Q28868	0/516		4 lots	Pass
			Q29440	0/492		0/2042	
NVM Endurance, Retention and Operating Life	AEC Q100-005 25°C	3 lots, N=>38	Q26230	0/40			
			Q26233	0/40			
			Q28728	0/156		4 lots	Pass
			Q28730	0/156		0/392	
NVM Endurance, Retention and Operating Life	AEC Q100-005 125°C	3 lots, N=>39	Q26231	0/40			
			Q26232	0/40			
			Q28727	0/126		4 lots	Pass
			Q28729	0/126		0/332	

CPTxxx Qualification Report



W7101F1 - Product Qualification Report Record Rev. H

The information contained in this document is PROPRIETARY to Silicon Laboratories, Inc. and shall not be reproduced or used in part or whole without Silicon Laboratories' written consent. The document is uncontrolled if printed or electronically saved.

CPTxxx, TSMC 0.18um Fabrication							
Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status
Test Group E – Electrical Verification							
ESD-HBM	JA114	1 lot, N=>3	Q33027				2.5kV
ESD-CDM	JC101	1 lot, N=>3	Q33238				2kV
Latch Up	JESD78 ±200mA Overvoltage = 3.6V	1 lot, N=>3	Q33029 Q33028	85 °C 25 °C			Pass Pass

Notes:

1 - Preceeded by MSL1, 260°C Preconditioning

This report applies to the following part numbers:
CPT007B-A02-GM CPT112S-A02-GM